



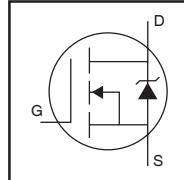
AUTOMOTIVE GRADE

# AUIRFR4104 AUIRFU4104

HEXFET® Power MOSFET

## Features

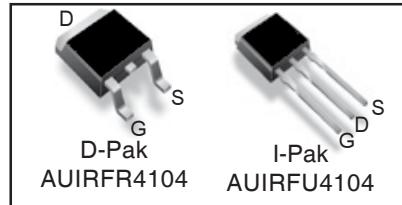
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*



$V_{(BR)DSS}$	<b>40V</b>
$R_{DS(on)}$ max.	<b>5.5mΩ</b>
$I_D$ (Silicon Limited)	<b>119A</b>
$I_D$ (Package Limited)	<b>42A</b>

## Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

## Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature ( $T_A$ ) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
$I_D$ @ $T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V (Silicon Limited)	119	A
$I_D$ @ $T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V	84	
$I_D$ @ $T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V (Package Limited)	42	
$I_{DM}$	Pulsed Drain Current ①	480	
$P_D$ @ $T_C = 25^\circ\text{C}$	Power Dissipation	140	W
	Linear Derating Factor	0.95	W/ $^\circ\text{C}$
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy (Thermally Limited) ②	145	mJ
$E_{AS}$ (tested )	Single Pulse Avalanche Energy Tested Value ⑥	310	
$I_{AR}$	Avalanche Current ①	See Fig.12a, 12b, 15, 16	A
$E_{AR}$	Repetitive Avalanche Energy ③		mJ
$T_J$	Operating Junction and	-55 to + 175	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case )		
	Mounting Torque, 6-32 or M3 screw	300	
		10 lbf·in (1.1N·m)	

## Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ④	—	1.05	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mount) ⑦	—	40	
$R_{\theta JA}$	Junction-to-Ambient	—	110	

## Static Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	40	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.032	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	4.3	5.5	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 42\text{A}$ ③
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 100\mu\text{A}$
$g_{fs}$	Forward Transconductance	58	—	—	S	$V_{DS} = 10V, I_D = 42\text{A}$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{DS} = 40V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{GS} = -20V$

## Dynamic Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$Q_g$	Total Gate Charge	—	59	89	nC	$I_D = 42\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	19	—		$V_{DS} = 32V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	24	—		$V_{GS} = 10V$ ③
$t_{d(on)}$	Turn-On Delay Time	—	17	—	ns	$V_{DD} = 20V$
$t_r$	Rise Time	—	69	—		$I_D = 42\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	37	—		$R_G = 6.8 \Omega$
$t_f$	Fall Time	—	36	—		$V_{GS} = 10V$ ③
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{iss}$	Input Capacitance	—	2950	—		
$C_{oss}$	Output Capacitance	—	660	—	pF	$V_{GS} = 0V$
$C_{rss}$	Reverse Transfer Capacitance	—	370	—		$V_{DS} = 25V$
$C_{oss}$	Output Capacitance	—	2130	—		$f = 1.0\text{MHz}$
$C_{oss}$	Output Capacitance	—	590	—		$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	850	—		$V_{GS} = 0V, V_{DS} = 32V, f = 1.0\text{MHz}$
						$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V$ ④

## Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	42	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	480		
$V_{SD}$	Diode Forward Voltage	—	—	1.3		$T_J = 25^\circ\text{C}, I_S = 42\text{A}, V_{GS} = 0V$ ③
$t_{rr}$	Reverse Recovery Time	—	28	42	ns	$T_J = 25^\circ\text{C}, I_F = 42\text{A}, V_{DD} = 20V$
$Q_{rr}$	Reverse Recovery Charge	—	24	36	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $LS+LD$ )				



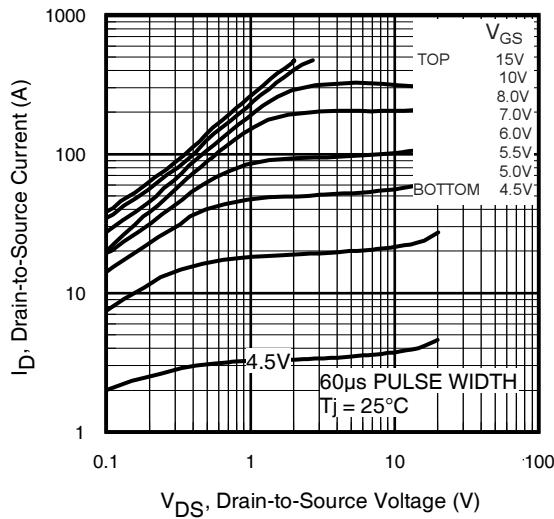
AUIRFR/U4104

**Qualification Information<sup>†</sup>**

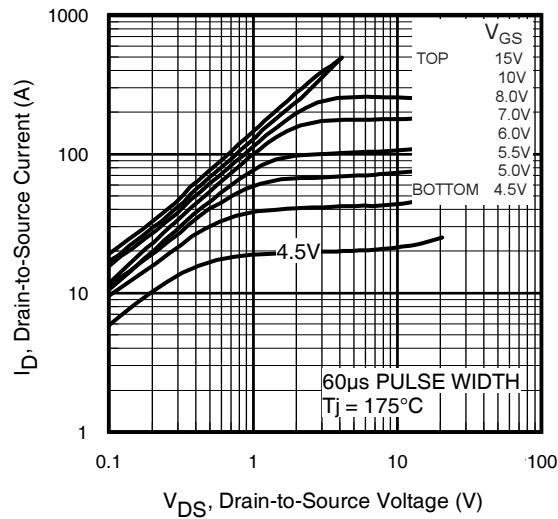
<b>Qualification Level</b>		Automotive (per AEC-Q101) <sup>††</sup>	
Comments: This part number(s) passed Automotive qualification. IR's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.			
<b>Moisture Sensitivity Level</b>	D-PAK	MSL1	
	I-PAK	MSL1	
<b>ESD</b>	Machine Model	Class M4 AEC-Q101-002	
	Human Body Model	Class H1C AEC-Q101-001	
	Charged Device Model	Class C3 AEC-Q101-005	
<b>RoHS Compliant</b>		Yes	

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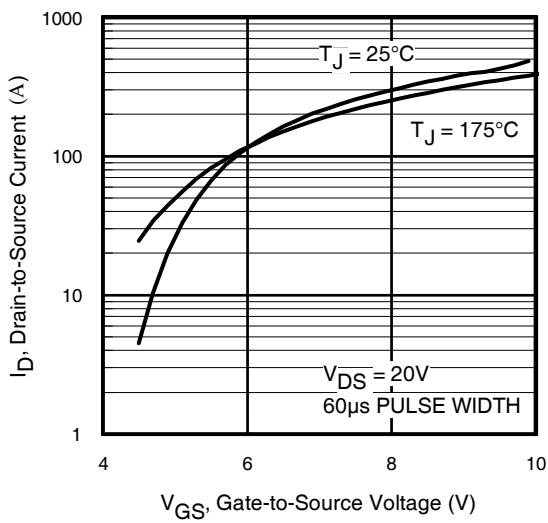
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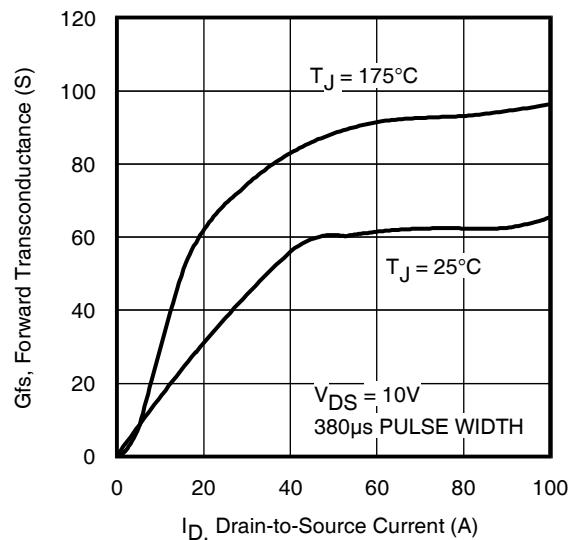
**Fig 1.** Typical Output Characteristics



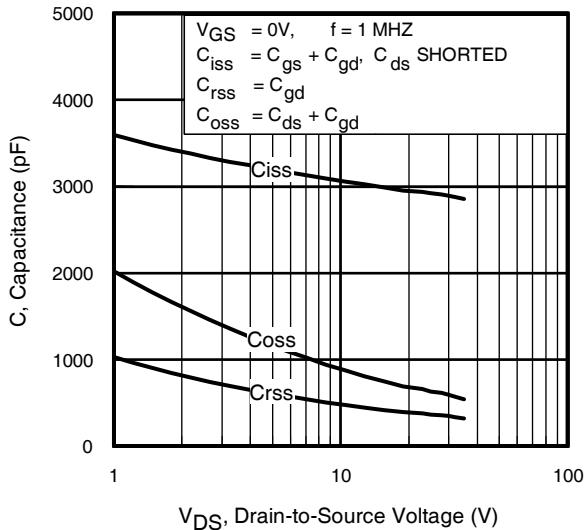
**Fig 2.** Typical Output Characteristics



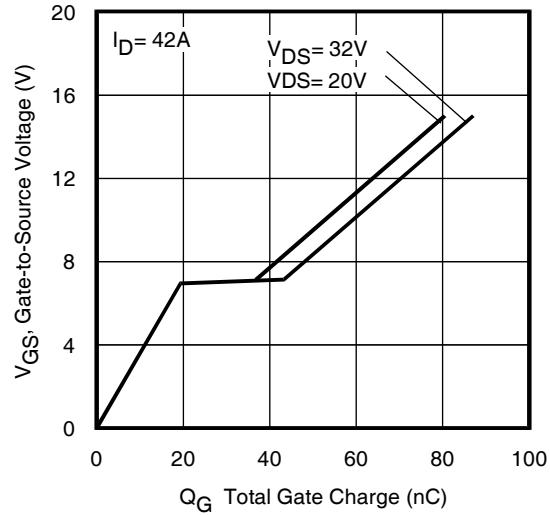
**Fig 3.** Typical Transfer Characteristics



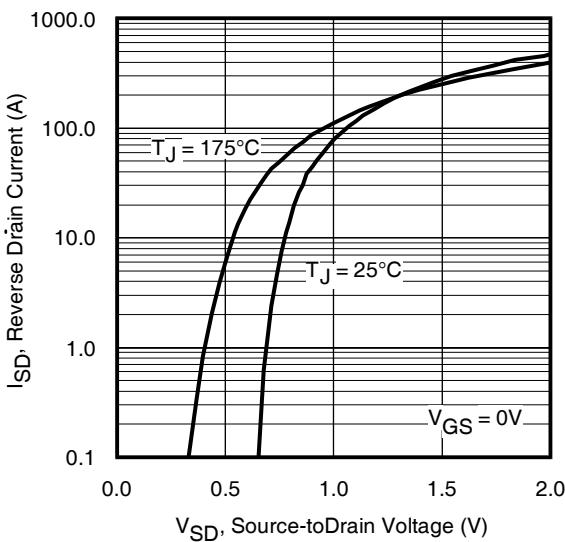
**Fig 4.** Typical Forward Transconductance Vs. Drain Current



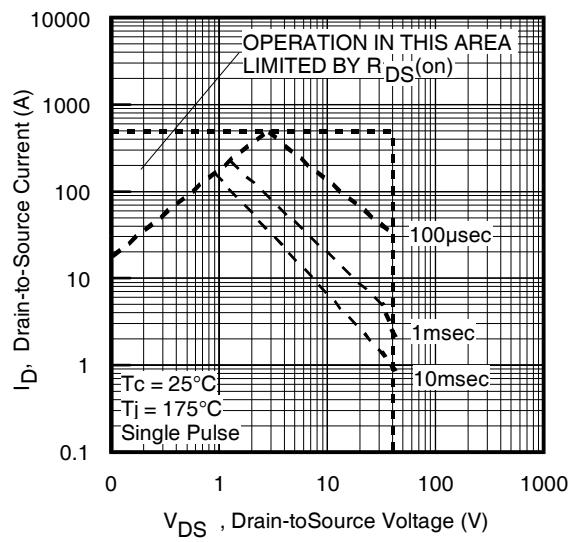
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



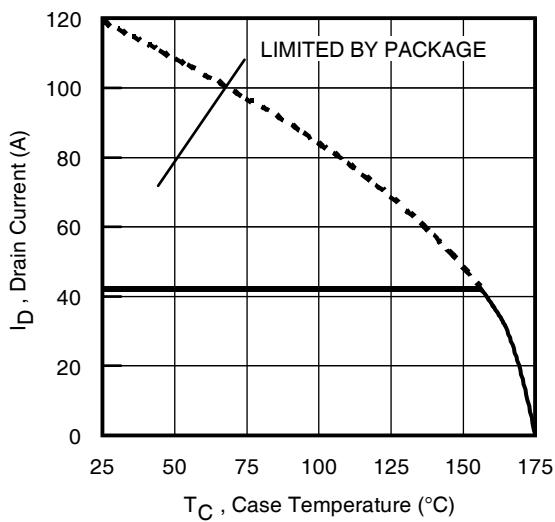
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



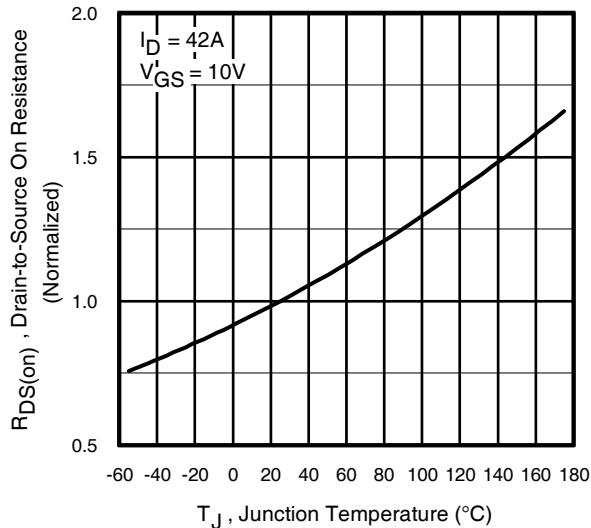
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



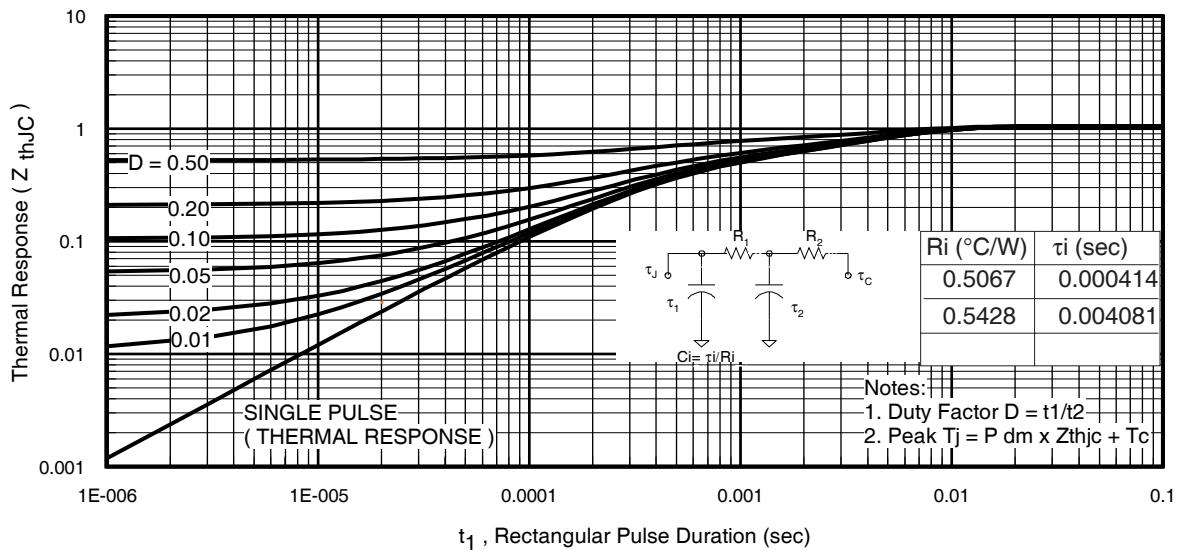
**Fig 8.** Maximum Safe Operating Area



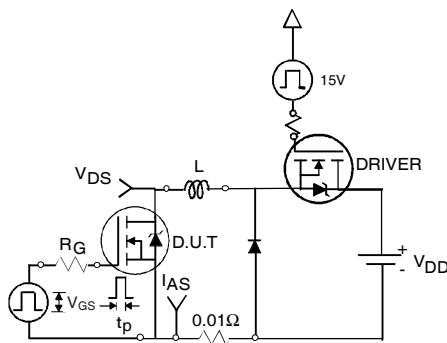
**Fig 9.** Maximum Drain Current Vs.  
Case Temperature



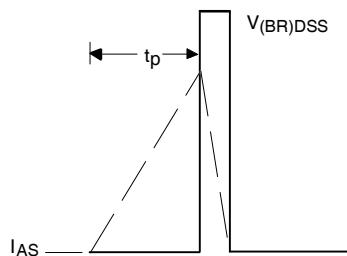
**Fig 10.** Normalized On-Resistance  
Vs. Temperature



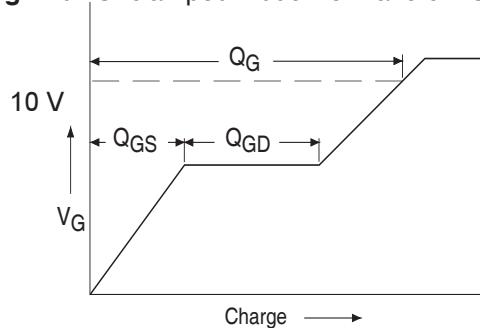
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



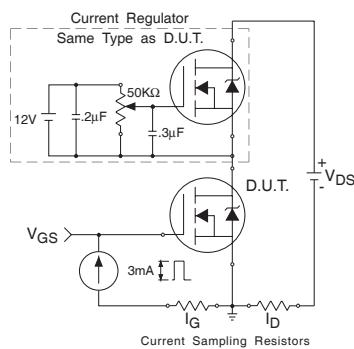
**Fig 12a.** Unclamped Inductive Test Circuit



**Fig 12b.** Unclamped Inductive Waveforms

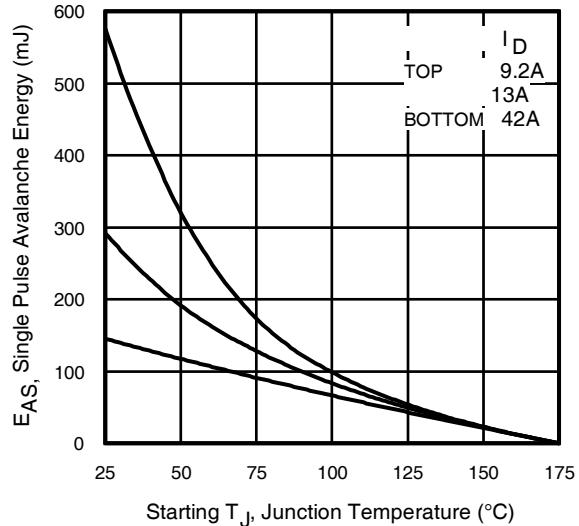


**Fig 13a.** Basic Gate Charge Waveform

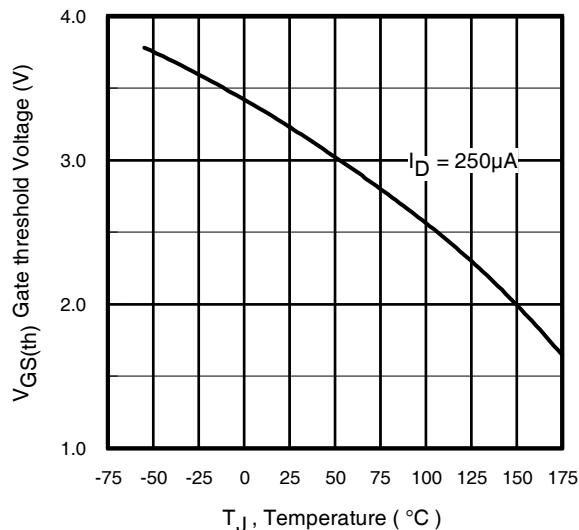


**Fig 13b.** Gate Charge Test Circuit

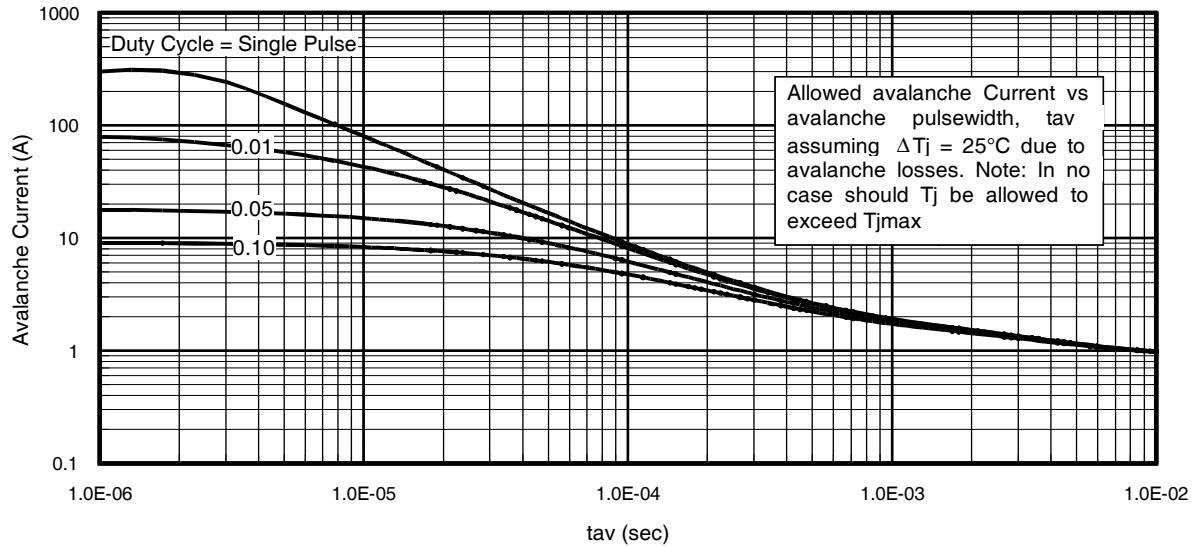
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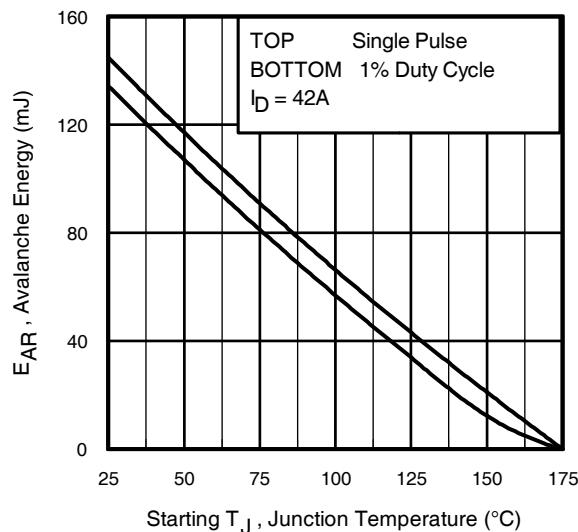
**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 14.** Threshold Voltage Vs. Temperature



**Fig 15.** Typical Avalanche Current Vs.Pulsewidth



**Fig 16.** Maximum Avalanche Energy Vs. Temperature

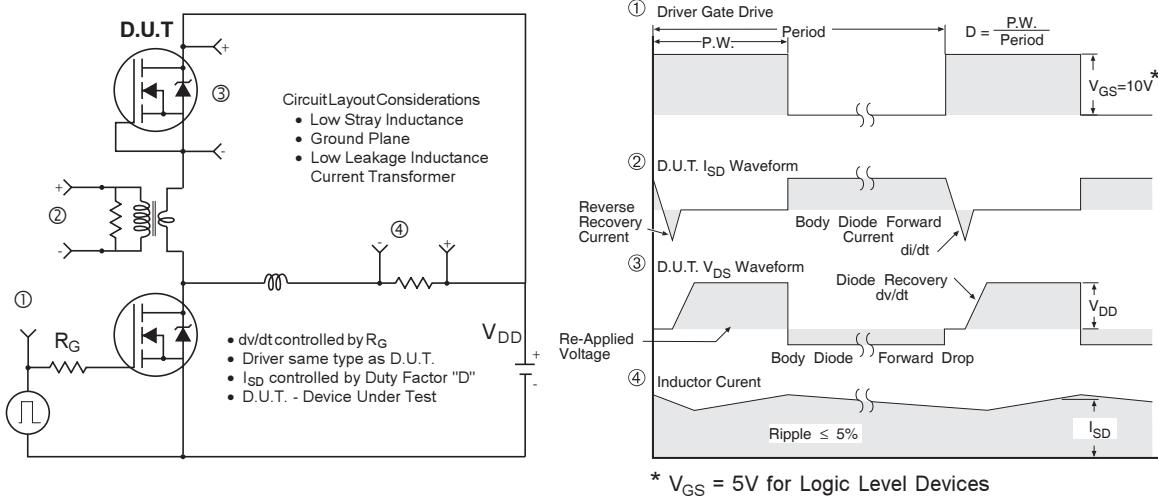
#### Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at [www.irf.com](http://www.irf.com))

1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4.  $P_{D(ave)} = \text{Average power dissipation per single avalanche pulse.}$
5.  $BV = \text{Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).}$
6.  $I_{av} = \text{Allowable avalanche current.}$
7.  $\Delta T = \text{Allowable rise in junction temperature, not to exceed } T_{jmax} \text{ (assumed as } 25^\circ\text{C in Figure 15, 16).}$
- $t_{av} = \text{Average time in avalanche.}$
- $D = \text{Duty cycle in avalanche} = t_{av} \cdot f$
- $Z_{thJC}(D, t_{av}) = \text{Transient thermal resistance, see figure 11)}$

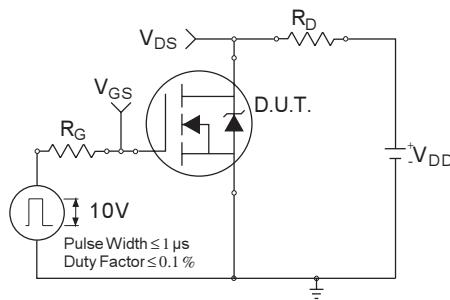
$$P_{D(ave)} = 1/2 ( 1.3 \cdot BV \cdot I_{av} ) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

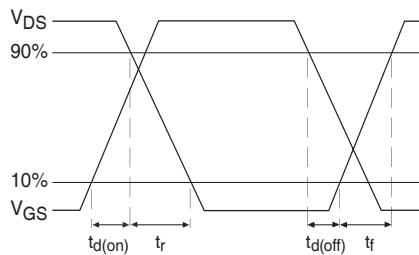
$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$



**Fig 17. Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs**



**Fig 18a. Switching Time Test Circuit**



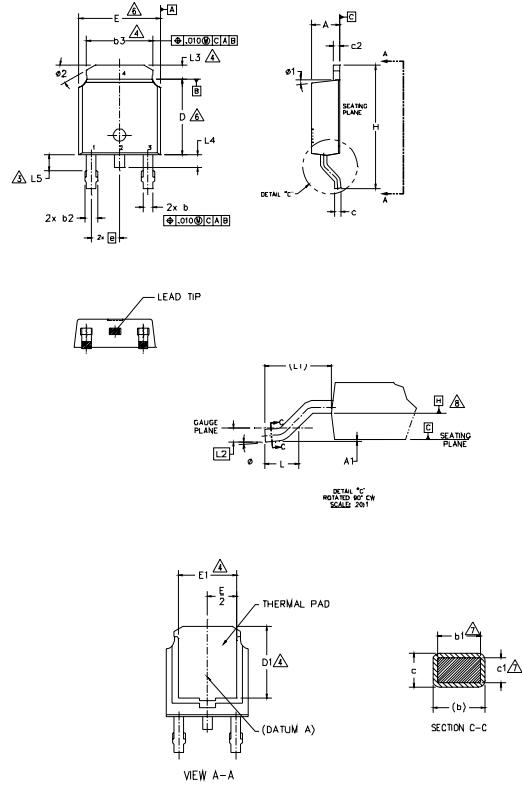
**Fig 18b. Switching Time Waveforms**

# AUIRFR/U4104



## D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



### NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- 3.- LEAD DIMENSION UNCONTROLLED IN L5.
- 4.- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- 6.- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- 7.- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 8.- DUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M B O L	DIMENSIONS		N O T E S
	MILLIMETERS	INCHES	
	MIN.	MAX.	
A	2.18	2.39	.086 .094
A1	—	0.13	— .005
b	0.64	0.89	.025 .035
b1	0.65	0.79	.025 .031
b2	0.76	1.14	.030 .045
b3	4.95	5.46	.195 .215
c	0.46	0.61	.018 .024
c1	0.41	0.56	.016 .022
c2	0.46	0.89	.018 .035
D	5.97	6.22	.235 .245
D1	5.21	—	.205 —
E	6.35	6.73	.250 .265
E1	4.32	—	.170 —
e	2.29	BSC	.090 BSC
H	9.40	10.41	.370 .410
L	1.40	1.78	.055 .070
L1	2.74	BSC	.108 REF.
L2	0.51	BSC	.020 BSC
L3	0.89	1.27	.035 .050
L4	—	1.02	— .040
L5	1.14	1.52	.045 .060
Ø	0°	10°	0° 10°
Ø1	0°	15°	0° 15°
Ø2	25°	35°	25° 35°

### LEAD ASSIGNMENTS

#### HEXFET

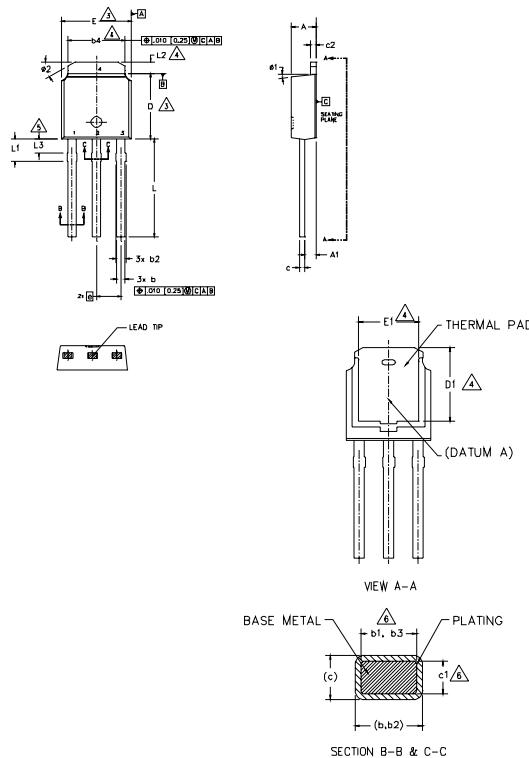
- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

#### IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter
- 4.- COLLECTOR

## I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



**NOTES:**

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS]
- 3.- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4.- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION b4, L2, E1 & D1.
- 5.- LEAD DIMENSION UNCONTROLLED IN L3.
- 6.- DIMENSION b1, b3 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION : INCHES.

S Y M B O L	DIMENSIONS		N O T E S	
	MILLIMETERS	INCHES		
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.39	.086	.094
A1	0.89	1.14	.035	.045
b	0.64	0.89	.025	.035
b1	0.65	0.79	.025	.031
b2	0.76	1.14	.030	.045
b3	0.76	1.04	.030	.041
b4	4.95	5.46	.195	.215
c	0.46	0.61	.018	.024
c1	0.41	0.56	.016	.022
c2	0.46	0.89	.018	.035
D	5.97	6.22	.235	.245
D1	5.21	—	.205	—
E	6.35	6.73	.250	.265
E1	4.32	—	.170	—
e	2.29 BSC	—	.090 BSC	—
L	8.89	9.65	.350	.380
L1	1.91	2.29	.045	.090
L2	0.89	1.27	.035	.050
L3	1.14	1.52	.045	.060
ø1	0°	15°	0°	15°
ø2	25°	35°	25°	35°

LEAD ASSIGNMENTS

HEXFET

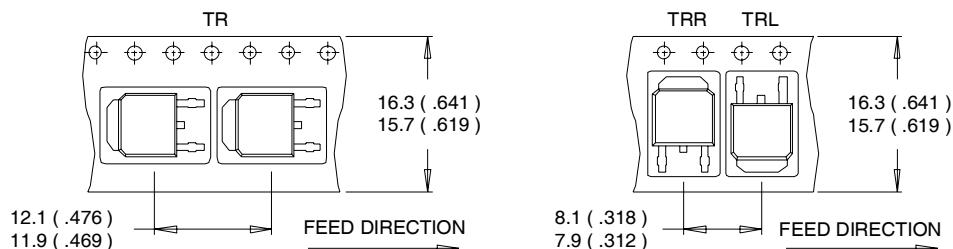
- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN



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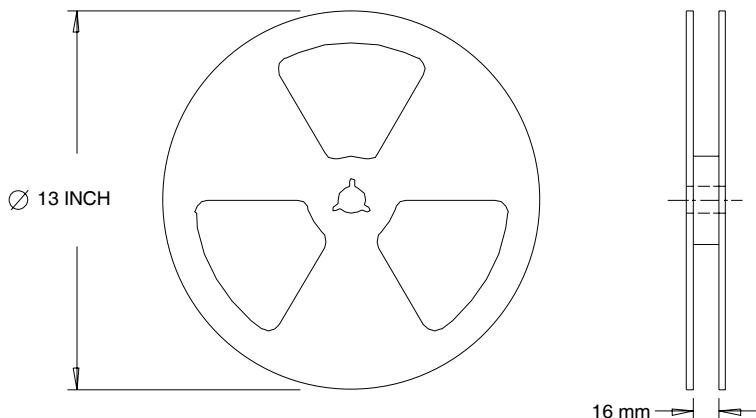
## D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



### NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS ( INCHES ).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



### NOTES :

1. OUTLINE CONFORMS TO EIA-481.

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25^\circ C$ ,  $L = 0.16mH$   $R_G = 25\Omega$ ,  $I_{AS} = 42A$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value.
- ③ Pulse width  $\leq 1.0ms$ ; duty cycle  $\leq 2\%$ .
- ④  $C_{oss}$  eff. is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑤ Limited by  $T_{Jmax}$ , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population, starting  $T_J = 25^\circ C$ ,  $L = 0.16mH$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 42A$ ,  $V_{GS} = 10V$ .
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ⑧  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ C$ .



AUIRFR/U4104

### Ordering Information

Base part	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRFR4104	Dpak	Tube	75	AUIRFR4104
		Tape and Reel	2000	AUIRFR4104TR
		Tape and Reel Left	3000	AUIRFR4104TRL
		Tape and Reel Right	3000	AUIRFR4104TRR
AUIRFU4104	Ipak	Tube	75	AUIRFU4104

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